

# MC100EP195B

## 3.3V ECL Programmable Delay Chip

### Descriptions

The MC100EP195B is a Programmable Delay Chip (PDC) designed primarily for clock deskewing and timing adjustment. It provides variable delay of a differential NECL/PECL input transition.

The delay section consists of a programmable matrix of gates and multiplexers as shown in the logic diagram, Figure 2. The delay increment of the EP195B has a digitally selectable resolution of about 10 ps and a net range of up to 10.2 ns. The required delay is selected by the 10 data select inputs D[9:0] values and controlled by the LEN (pin 10). A LOW level on LEN allows a transparent LOAD mode of real time delay values by D[9:0]. A LOW to HIGH transition on LEN will LOCK and HOLD current values present against any subsequent changes in D[10:0]. The approximate delay values for varying tap numbers correlating to D0 (LSB) through D9 (MSB) are shown in Table 6 and Figure 3.

The IN/ $\overline{\text{IN}}$  inputs can accept LVPECL (SE of Diff), or LVDS level signals. Because the EP195B is designed using a chain of multiplexers it has a fixed minimum delay of 2.2 ns. An additional pin D10 is provided for controlling Pins 14 and 15, CASCADE and  $\overline{\text{CASCADE}}$ , also latched by LEN, in cascading multiple PDCs for increased programmable range. The cascade logic allows full control of multiple PDCs. Switching devices from all "1" states on D[0:9] with SETMAX LOW to all "0" states on D[0:9] with SETMAX HIGH will increase the delay equivalent to "D0", the minimum increment.

Select input pins D[10:0] may be threshold controlled by combinations of interconnects between  $V_{\text{EF}}$  (pin 7) and  $V_{\text{CF}}$  (pin 8) for LVC MOS, ECL, or LVTTL level signals. For LVC MOS input levels, leave  $V_{\text{CF}}$  and  $V_{\text{EF}}$  open. For ECL operation, short  $V_{\text{CF}}$  and  $V_{\text{EF}}$  (Pins 7 and 8). For LVTTL level operation, connect a 1.5 V supply reference to  $V_{\text{CF}}$  and leave open  $V_{\text{EF}}$  pin. The 1.5 V reference voltage to  $V_{\text{CF}}$  pin can be accomplished by placing a 2.2 k $\Omega$  resistor between  $V_{\text{CF}}$  and  $V_{\text{EE}}$  for a 3.3 V power supply.

The  $V_{\text{BB}}$  pin, an internally generated voltage supply, is available to this device only. For single-ended input conditions, the unused differential input is connected to  $V_{\text{BB}}$  as a switching reference voltage.  $V_{\text{BB}}$  may also rebias AC coupled inputs. When used, decouple  $V_{\text{BB}}$  and  $V_{\text{CC}}$  via a 0.01  $\mu\text{F}$  capacitor and limit current sourcing or sinking to 0.5 mA. When not used,  $V_{\text{BB}}$  should be left open.

The 100 Series contains temperature compensation.

### Features

- Maximum Input Clock Frequency >1.2 GHz Typical
- Programmable Range: 0 ns to 10 ns
- Delay Range: 2.2 ns to 12.2 ns
- 10 ps Increments
- PECL Mode Operating Range:  
 $V_{\text{CC}} = 3.0 \text{ V to } 3.6 \text{ V with } V_{\text{EE}} = 0 \text{ V}$
- NECL Mode Operating Range:  
 $V_{\text{CC}} = 0 \text{ V with } V_{\text{EE}} = -3.0 \text{ V to } -3.6 \text{ V}$
- IN/ $\overline{\text{IN}}$  Inputs Accept LVPECL, LVNECL, LVDS Levels
- A Logic High on the  $\overline{\text{EN}}$  Pin Will Force Q to Logic Low
- D[10:0] Can Select Either LVPECL, LVC MOS, or LVTTL Input Levels
- $V_{\text{BB}}$  Output Reference Voltage
- These are Pb-Free Devices



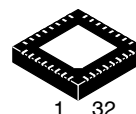
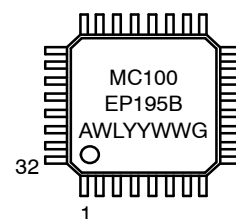
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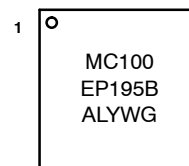
### MARKING DIAGRAMS\*



LQFP-32  
FA SUFFIX  
CASE 873A



QFN32  
MN SUFFIX  
CASE 488AM



A = Assembly Location  
WL, L = Wafer Lot  
Y, YY = Year  
W, WW = Work Week  
G = Pb-Free Package

\*For additional marking information, refer to Application Note AND8002/D.

### ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 15 of this data sheet.

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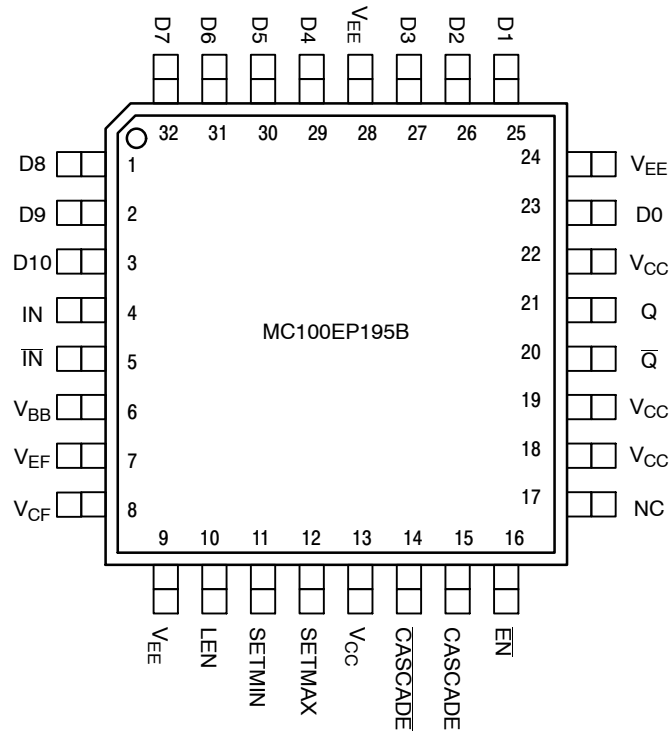


Figure 1. 32-Lead LQFP Pinout (Top View)

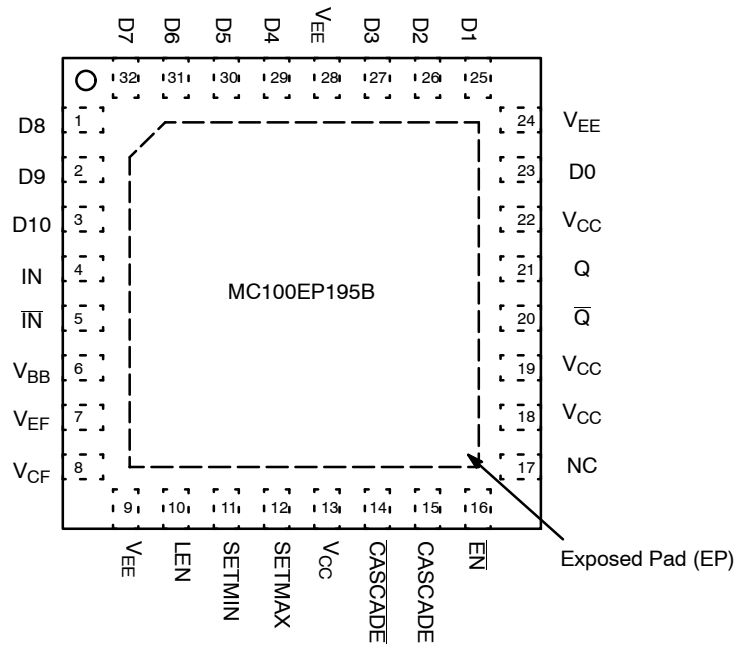


Figure 1. 32-Lead QFN (Top View)

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**Table 1. PIN DESCRIPTION**

Pin	Name	I/O	Default State	Description
23, 25, 26, 27, 29, 30, 31, 32, 1, 2	D[0:9]	LVC MOS, LV TTL, ECL Input	Low	Single-Ended Parallel Data Inputs [0:9]. Internal 75 k $\Omega$ to V <sub>EE</sub> . (Note 1)
3	D[10]	LVC MOS, LV TTL, ECL Input	Low	Single-Ended CASCADE/CASCADE Control Input. Internal 75 k $\Omega$ to V <sub>EE</sub> . (Note 1)
4	IN	LVPECL, LVDS	Low	Noninverted Differential Input. Internal 75 k $\Omega$ to V <sub>EE</sub> .
5	$\overline{\text{IN}}$	LVPECL, LVDS	High	Inverted Differential Input. Internal 75 k $\Omega$ to V <sub>EE</sub> and 36.5 k $\Omega$ to V <sub>CC</sub> .
6	V <sub>BB</sub>	-	-	ECL Reference Voltage Output
7	V <sub>EF</sub>	-	-	Reference Voltage for ECL Mode Connection
8	V <sub>CF</sub>	-	-	LVC MOS, ECL, OR LV TTL Input Mode Select
9, 24, 28	V <sub>EE</sub>	-	-	Negative Supply Voltage. All V <sub>EE</sub> Pins must be Externally Connected to Power Supply to Guarantee Proper Operation. (Note 2)
13, 18, 19, 22	V <sub>CC</sub>	-	-	Positive Supply Voltage. All V <sub>CC</sub> Pins must be externally Connected to Power Supply to Guarantee Proper Operation. (Note 2)
10	LEN	ECL Input	Low	Single-ended D pins LOAD / HOLD input. Internal 75 k $\Omega$ to V <sub>EE</sub> .
11	SETMIN	ECL Input	Low	Single-ended Minimum Delay Set Logic Input. Internal 75 k $\Omega$ to V <sub>EE</sub> . (Note 1)
12	SETMAX	ECL Input	Low	Single-ended Maximum Delay Set Logic Input. Internal 75 k $\Omega$ to V <sub>EE</sub> . (Note 1)
14	$\overline{\text{CASCADE}}$	ECL Output	-	Inverted Differential Cascade Output for D[10]. Typically Terminated with 50 $\Omega$ to V <sub>TT</sub> = V <sub>CC</sub> - 2 V.
15	CASCADE	ECL Output	-	Noninverted Differential Cascade Output. for D[10] Typically Terminated with 50 $\Omega$ to V <sub>TT</sub> = V <sub>CC</sub> - 2 V.
16	$\overline{\text{EN}}$	ECL Input	Low	Single-ended Output Enable Pin. Internal 75 k $\Omega$ to V <sub>EE</sub> .
17	NC	-	-	No Connect. The NC Pin is Electrically Connected to the Die and "MUST BE" Left Open
21	Q	ECL Output	-	Noninverted Differential Output. Typically Terminated with 50 $\Omega$ to V <sub>TT</sub> = V <sub>CC</sub> - 2 V.
20	$\overline{\text{Q}}$	ECL Output	-	Inverted Differential Output. Typically Terminated with 50 $\Omega$ to V <sub>TT</sub> = V <sub>CC</sub> - 2 V.

1. SETMIN will override SETMAX if both are high. SETMAX and SETMIN will override all D[0:10] inputs.
2. All V<sub>CC</sub> and V<sub>EE</sub> pins must be externally connected to Power Supply to guarantee proper operation.

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**Table 2. CONTROL PIN**

Pin	State	Function
EN	LOW (Note 3)	Input Signal is Propagated to the Output
	HIGH	Output Holds Logic Low State
LEN	LOW (Note 3)	Transparent or LOAD mode for real time delay values present on D[0:10].
	HIGH	LOCK and HOLD mode for delay values on D[0:10]; further changes on D[0:10] are not recognized and do not affect delay.
SETMIN	LOW (Note 3)	Output Delay set by D[0:10]
	HIGH	Set Minimum Output Delay
SETMAX	LOW (Note 3)	Output Delay set by D[0:10]
	HIGH	Set Maximum Output Delay
D10	LOW (Note 3)	CASCADE Output LOW, CASCADE Output HIGH
	HIGH	CASCADE Output LOW, CASCADE Output HIGH

3. Internal pulldown resistor will provide a logic LOW if pin is left unconnected.

**Table 3. CONTROL D[0:10] INTERFACE**

V <sub>CF</sub>	V <sub>EF</sub> Pin (Note 4)	ECL Mode
V <sub>CF</sub>	No Connect	LVC MOS Mode
V <sub>CF</sub>	1.5 V ± 100 mV	LVTTTL Mode (Note 5)

4. Short V<sub>CF</sub> (pin 8) and V<sub>EF</sub> (pin 7).

5. When Operating in LVTTTL Mode, the reference voltage can be provided by connecting an external resistor, R<sub>CF</sub> (suggested resistor value is 2.2 kΩ ± 5%), between V<sub>CF</sub> and V<sub>EE</sub> pins.

**Table 4. DATA INPUT ALLOWED OPERATING VOLTAGE MODE TABLE**

POWER SUPPLY	CONTROL DATA SELECT INPUTS PINS (D [0:10])			
	LVC MOS	LVTTTL	LVPECL	LVNECL
PECL Mode Operating Range	YES	YES	YES	N/A
NECL Mode Operating Range	N/A	N/A	N/A	YES

**Table 5. ATTRIBUTES**

Characteristics	Value	
Internal Input Pulldown Resistor (R1)	75 kΩ	
ESD Protection	Human Body Model	> 2 kV
	Machine Model	> 100 V
	Charged Device Model	> 2 kV
Moisture Sensitivity, Indefinite Time Out of Drypack (Note 6)	Pb-Free Pkg	
	QFN-32	Level 1
	LQFP-32	Level 2
Flammability Rating Oxygen Index: 28 to 34	UL 94 V-0 @ 0.125 in	
Transistor Count	1217 Devices	
Meets or exceeds JEDEC Spec EIA/JESD78 IC Latchup Test		

6. For additional information, see Application Note AND8003/D.

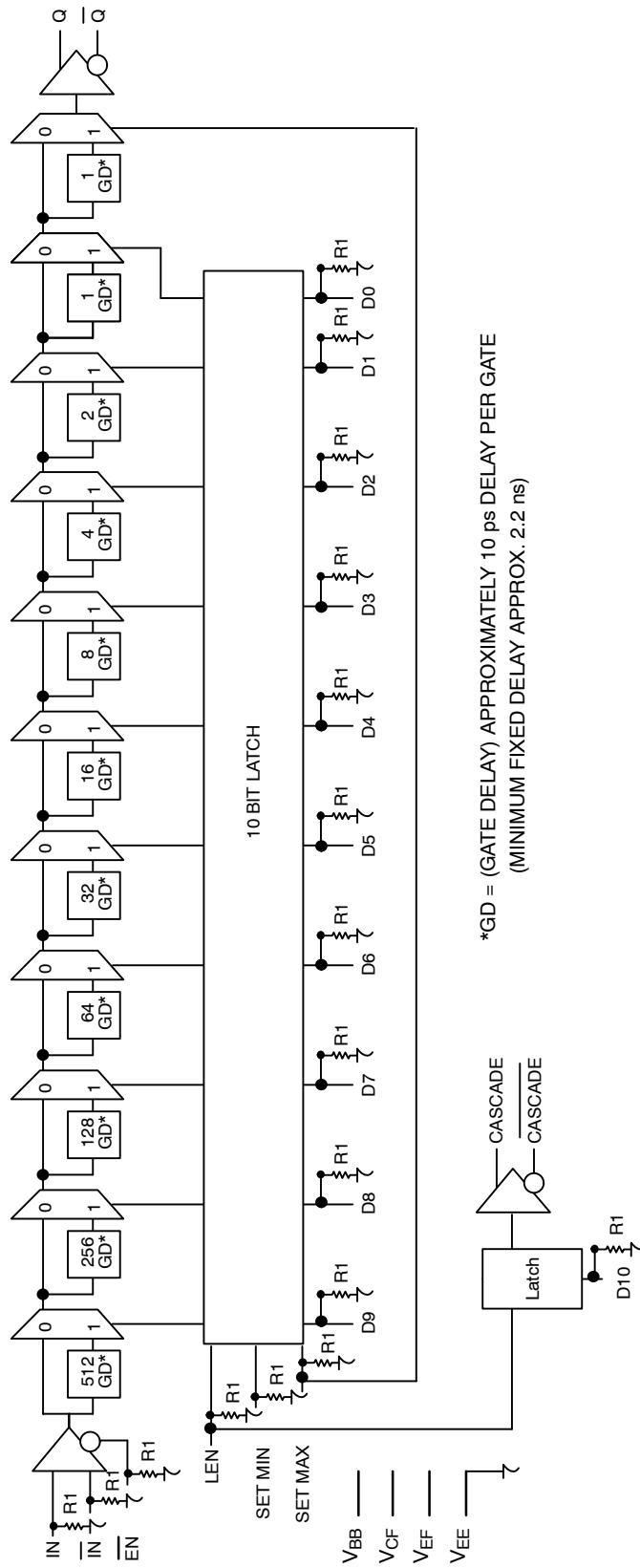


Figure 2. Logic Diagram

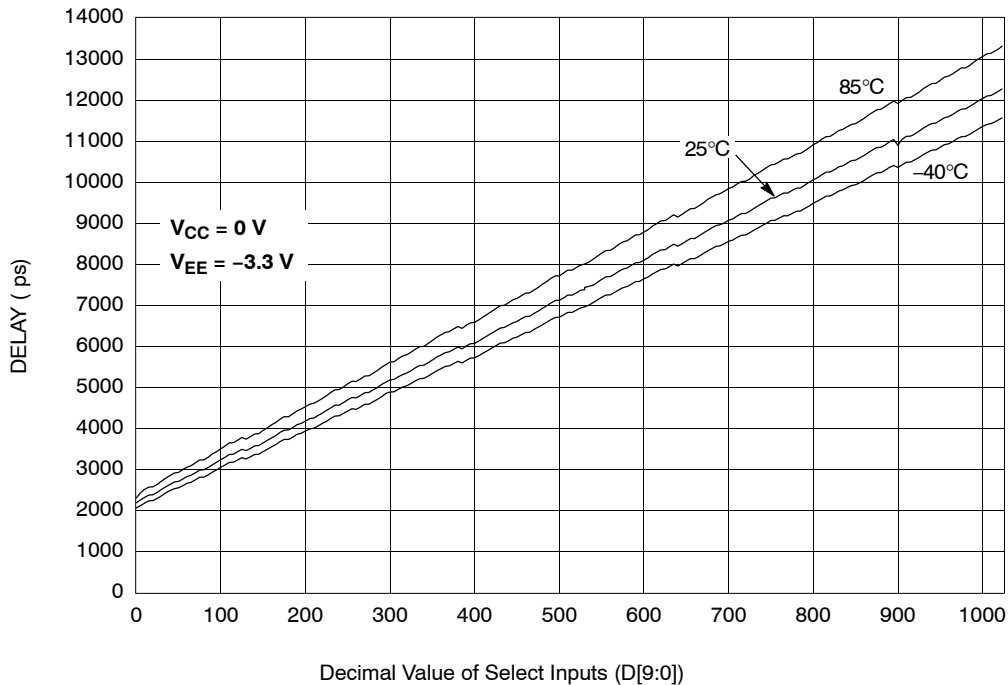
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**Table 6. THEORETICAL DELAY VALUES**

D(9:0) Value	SETMIN	SETMAX	Programmable Delay*
XXXXXXXXXX	H	L	0 ps
000000000	L	L	0 ps
000000001	L	L	10 ps
000000010	L	L	20 ps
000000011	L	L	30 ps
000000100	L	L	40 ps
000000101	L	L	50 ps
000000110	L	L	60 ps
000000111	L	L	70 ps
000001000	L	L	80 ps
000010000	L	L	160 ps
000100000	L	L	320 ps
001000000	L	L	640 ps
001000000	L	L	1280 ps
010000000	L	L	2560 ps
100000000	L	L	5120 ps
111111111	L	L	10230 ps
XXXXXXXXXX	L	H	10240 ps

\*Fixed minimum delay not included.

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**Figure 3. Measured Delay vs. Select Inputs**

**Table 7. MAXIMUM RATINGS**

Symbol	Parameter	Condition 1	Condition 2	Rating	Unit
$V_{CC}$	Positive Mode Power Supply	$V_{EE} = 0\text{ V}$		6	V
$V_{EE}$	Negative Mode Power Supply	$V_{CC} = 0\text{ V}$		-6	V
$V_I$	Positive Mode Input Voltage Negative Mode Input Voltage	$V_{EE} = 0\text{ V}$ $V_{CC} = 0\text{ V}$	$V_I \leq V_{CC}$ $V_I \geq V_{EE}$	6 -6	V V
$I_{out}$	Output Current	Continuous Surge		50 100	mA mA
$I_{BB}$	$V_{BB}$ Sink/Source			$\pm 0.5$	mA
$T_A$	Operating Temperature Range			-40 to +85	°C
$T_{stg}$	Storage Temperature Range			-65 to +150	°C
$\theta_{JA}$	Thermal Resistance (Junction-to-Ambient)	0 lfpm 500 lfpm	QFN-32 QFN-32	31 27	°C/W °C/W
$\theta_{JC}$	Thermal Resistance (Junction-to-Case)	2S2P Standard Board	QFN-32	12	°C/W
$\theta_{JA}$	Thermal Resistance (Junction-to-Ambient)	0 lfpm 500 lfpm	LQFP-32 LQFP-32	80 55	°C/W °C/W
$\theta_{JC}$	Thermal Resistance (Junction-to-Case)	2S2P Standard Board	LQFP-32	12 to 17	°C/W
$T_{sol}$	Wave Solder	<2 to 3 sec @ 248°C		265 265	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

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**Table 8. 100EP DC CHARACTERISTICS, PECL  $V_{CC} = 3.3$  V,  $V_{EE} = 0$  V (Note 7)**

Symbol	Characteristic	-40°C			25°C			85°C			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
$I_{EE}$	Negative Power Supply Current	90	115	170	100	140	170	100	145	170	mA
$V_{OH}$	Output HIGH Voltage (Note 8)	2155	2280	2405	2155	2280	2405	2155	2280	2405	mV
$V_{OL}$	Output LOW Voltage (Note 8)	1355	1480	1605	1355	1480	1605	1355	1480	1605	mV
$V_{IH}$	Input HIGH Voltage (Single-Ended)										mV
	LVPECL	2075		2420	2075		2420	2075		2420	
	CMOS	2000		3300	2000		3300	2000		3300	
	TTL	2000		3300	2000		3300	2000		3300	
$V_{IL}$	Input LOW Voltage (Single-Ended)										mV
	LVPECL	1355		1675	1490		1675	1490		1675	
	CMOS	0		800	0		800	0		800	
	TTL	0		800	0		800	0		800	
$V_{BB}$	ECL Output Voltage Reference	1775	1875	1975	1775	1875	1975	1775	1875	1975	mV
$V_{CF}$	LVTTL Mode Input Detect Voltage	1.4	1.5	1.6	1.4	1.5	1.6	1.4	1.5	1.6	V
$V_{EF}$	Reference Voltage for ECL Mode Connection	1900	2020	2150	1900	2020	2150	1900	2020	2150	mV
$V_{IHCMR}$	Input HIGH Voltage Common Mode Range (Differential Configuration) (Note 9)	1.2		3.3	1.2		3.3	1.2		3.3	V
$I_{IH}$	Input HIGH Current (@ $V_{IH}$ )	0		150	0		150	0		150	$\mu$ A
$I_{IL}$	Input LOW Current (@ $V_{IL}$ )	0		150	0		150	0		150	$\mu$ A

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lpm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

7. Input and output parameters vary 1:1 with  $V_{CC}$ .  $V_{EE}$  can vary +0.3 V to -0.3 V.

8. All loading with 50  $\Omega$  to  $V_{CC} - 2.0$  V.

9.  $V_{IHCMR}$  min varies 1:1 with  $V_{EE}$ .  $V_{IHCMR}$  max varies 1:1 with  $V_{CC}$ . The  $V_{IHCMR}$  range is referenced to the most positive side of the differential input signal.



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**Table 9. 100EP DC CHARACTERISTICS, NECL**  $V_{CC} = 0\text{ V}$ ,  $V_{EE} = -3.3\text{ V}$  (Note 10)

Symbol	Characteristic	-40°C			25°C			85°C			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
$I_{EE}$	Negative Power Supply Current (Note 11)	90	115	170	100	140	170	100	145	170	mA
$V_{OH}$	Output HIGH Voltage (Note 12)	-1145	-1020	-895	-1145	-1020	-895	-1145	-1020	-895	mV
$V_{OL}$	Output LOW Voltage (Note 12)	-1945	-1820	-1695	-1945	-1820	-1695	-1945	-1820	-1695	mV
$V_{IH}$	Input HIGH Voltage (Single-Ended) LVNECL	-1225		-880	-1225		-880	-1225		-880	mV
$V_{IL}$	Input LOW Voltage (Single-Ended) LVNECL	-1945		-1625	-1945		-1625	-1945		-1625	mV
$V_{BB}$	ECL Output Voltage Reference	-1525	-1425	-1325	-1525	-1425	-1325	-1525	-1425	-1325	mV
$V_{EF}$	Reference Voltage for ECL Mode Connection	-1400	-1280	-1250	-1400	-1280	-1250	-1400	-1280	-1250	mV
$V_{IHCMR}$	Input HIGH Voltage Common Mode Range (Differential Configuration) (Note 13)	$V_{EE} + 1.2$		0.0	$V_{EE} + 1.2$		0.0	$V_{EE} + 1.2$		0.0	V
$I_{IH}$	Input HIGH Current (@ $V_{IH}$ )	0		150	0		150	0		150	$\mu\text{A}$
$I_{IL}$	Input LOW Current (@ $V_{IL}$ )	0		150	0		150	0		150	$\mu\text{A}$

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

10. Input and output parameters vary 1:1 with  $V_{CC}$ .  $V_{EE}$  can vary +0.3 V to -0.3 V.

11. Required 500 lfm air flow when using +5 V power supply. For  $(V_{CC} - V_{EE}) > 3.3\text{ V}$ ,  $5\ \Omega$  to  $10\ \Omega$  in line with  $V_{EE}$  required for maximum thermal protection at elevated temperatures. Recommend  $V_{CC} - V_{EE}$  operation at  $\leq 3.8\text{ V}$ .

12. All loading with  $50\ \Omega$  to  $V_{CC} - 2.0\text{ V}$ .

13.  $V_{IHCMR}$  min varies 1:1 with  $V_{EE}$ .  $V_{IHCMR}$  max varies 1:1 with  $V_{CC}$ . The  $V_{IHCMR}$  range is referenced to the most positive side of the differential input signal.

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**Table 10. AC CHARACTERISTICS**  $V_{CC} = 0\text{ V}$ ;  $V_{EE} = -3.0\text{ V}$  to  $-3.6\text{ V}$  or  $V_{CC} = 3.0\text{ V}$  to  $3.6\text{ V}$ ;  $V_{EE} = 0\text{ V}$  (Note 14)

Symbol	Characteristic	-40°C			25°C			85°C			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
$f_{max}$	Maximum Frequency		1.2			1.2			1.2		GHz
$V_{outPP}$	Output Voltage Amplitude	610	820		610	820		610	820		mV
$t_{PLH}$ $t_{PHL}$	Propagation Delay IN to Q; D(0-10) = 0, SETMIN IN to Q; D(0-10) = 1023, SETMAX EN to Q; D(0-10) = 0 D0 to CASCADE	2000 10900 1990 375	2400 12400 2500 475	2800 13900 2990 575	2150 11500 2130 400	2500 13000 2600 500	2950 14500 3130 600	2250 12250 2380 425	2700 13750 2800 525	3050 15250 3380 625	ps
$t_{RANGE}$	Programmable Range $t_{PD}(\text{max}) - t_{PD}(\text{min})$	8950	9950	10950	9450	10450	11450	10110	11100	12110	ps
$\Delta t$	Step Delay (Note 15)  D0 High D1 High D2 High D3 High D4 High D5 High D6 High D7 High D8 High D9 High		10 16 32 65 155 310 620 1200 2500 4900			11 18 33 72 165 325 650 1300 2600 5200				15 26 46 92 195 370 720 1400 2800 5500	ps
NLIN	Non-Linearity (Note 21) 0 to 511 Decimal Values for D[9:0] Range 512 to 1024 Decimal Values for D[9:0] Range 1 to 1023 Decimal Values for D[9:0] Range		$\pm 7.0$ $\pm 7.0$ $\pm 11$			$\pm 7.0$ $\pm 7.0$ $\pm 11$			$\pm 11$ $\pm 11$ $\pm 18$		ps
$t_{SKEW}$	Duty Cycle Skew (Note 16) $ t_{PHL} - t_{PLH} $		25	90		25	90		25	90	ps
$t_s$	Setup Time  D to LEN D to IN (Note 17) EN to IN (Note 18)	200 500 300	-40 -550 100		200 500 300	-40 -590 100		200 500 300	-40 -650 120		ps
$t_h$	Hold Time  LEN to D IN to EN (Note 19)	200 400	50 -320		200 400	40 -350		200 400	30 -400		ps
$t_R$	Release Time  EN to IN (Note 20) SET MAX to LEN SET MIN to LEN	300 400 350	-150 180 220		300 400 350	-170 200 250		300 400 350	-200 210 260		ps
$t_{jitter}$	RMS Random Clock Jitter @ 1.2 GHz IN to Q; D(0:10) = 0 or SETMIN IN to Q; D(0:10) = 1023 or SETMAX		0.9 1.9	2.0 5.0		1.1 2.6	2.0 5.0		1.2 3.3	2.0 5.0	ps

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

14. Measured using a 750 mV source, 50% duty cycle clock source. All loading with  $50\ \Omega$  to  $V_{CC} - 2.0\text{ V}$ .

15. Specification limits represent the amount of delay added with the assertion of each individual delay control pin. The various combinations of asserted delay control inputs will typically realize D0 resolution steps across the specified programmable range.

16. Duty cycle skew guaranteed only for differential operation measured from the cross point of the input to the cross point of the output.

17. This setup time defines the amount of time prior to the input signal the delay tap of the device must be set.

18. This setup time is the minimum time that EN must be asserted prior to the next transition of IN/IN to prevent an output response greater than  $\pm 75\text{ mV}$  to that IN/IN transition.

19. This hold time is the minimum time that EN must remain asserted after a negative going IN or positive going IN to prevent an output response greater than  $\pm 75\text{ mV}$  to that IN/IN transition.

20. This release time is the minimum time that EN must be deasserted prior to the next IN/IN transition to ensure an output response that meets the specified IN to Q propagation delay and transition times.

21. Deviation from a linear delay (actual Min to Max) in the 1024 programmable steps.

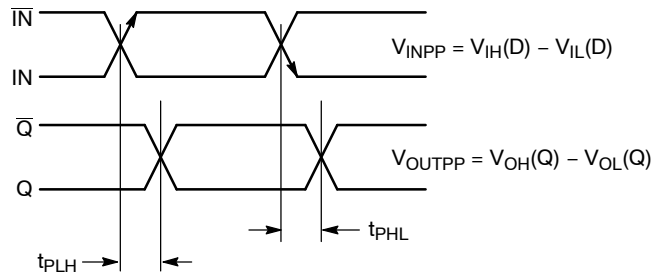
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**Table 10. AC CHARACTERISTICS**  $V_{CC} = 0\text{ V}$ ;  $V_{EE} = -3.0\text{ V to } -3.6\text{ V}$  or  $V_{CC} = 3.0\text{ V to } 3.6\text{ V}$ ;  $V_{EE} = 0\text{ V}$  (Note 14)

Symbol	Characteristic	-40°C			25°C			85°C			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
$V_{PP}$	Input Voltage Swing (Differential Configuration)	150	800	1200	150	800	1200	150	800	1200	mV
$t_r$ $t_f$	Output Rise/Fall Time @ 50 MHz 20–80% (Q) 20–80% (CASCADE)	85 110	115 160	140 210	100 120	120 175	140 230	100 120	130 190	165 250	ps

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfm. Electrical parameters are guaranteed only over the declared operating temperature range. Functional operation of the device exceeding these conditions is not implied. Device specification limit values are applied individually under normal operating conditions and not valid simultaneously.

14. Measured using a 750 mV source, 50% duty cycle clock source. All loading with  $50\ \Omega$  to  $V_{CC} - 2.0\text{ V}$ .
15. Specification limits represent the amount of delay added with the assertion of each individual delay control pin. The various combinations of asserted delay control inputs will typically realize D0 resolution steps across the specified programmable range.
16. Duty cycle skew guaranteed only for differential operation measured from the cross point of the input to the cross point of the output.
17. This setup time defines the amount of time prior to the input signal the delay tap of the device must be set.
18. This setup time is the minimum time that  $\overline{EN}$  must be asserted prior to the next transition of  $IN/\overline{IN}$  to prevent an output response greater than  $\pm 75\text{ mV}$  to that  $IN/\overline{IN}$  transition.
19. This hold time is the minimum time that  $\overline{EN}$  must remain asserted after a negative going  $IN$  or positive going  $\overline{IN}$  to prevent an output response greater than  $\pm 75\text{ mV}$  to that  $IN/\overline{IN}$  transition.
20. This release time is the minimum time that  $\overline{EN}$  must be deasserted prior to the next  $IN/\overline{IN}$  transition to ensure an output response that meets the specified  $IN$  to  $Q$  propagation delay and transition times.
21. Deviation from a linear delay (actual Min to Max) in the 1024 programmable steps.



**Figure 4. AC Reference Measurement**

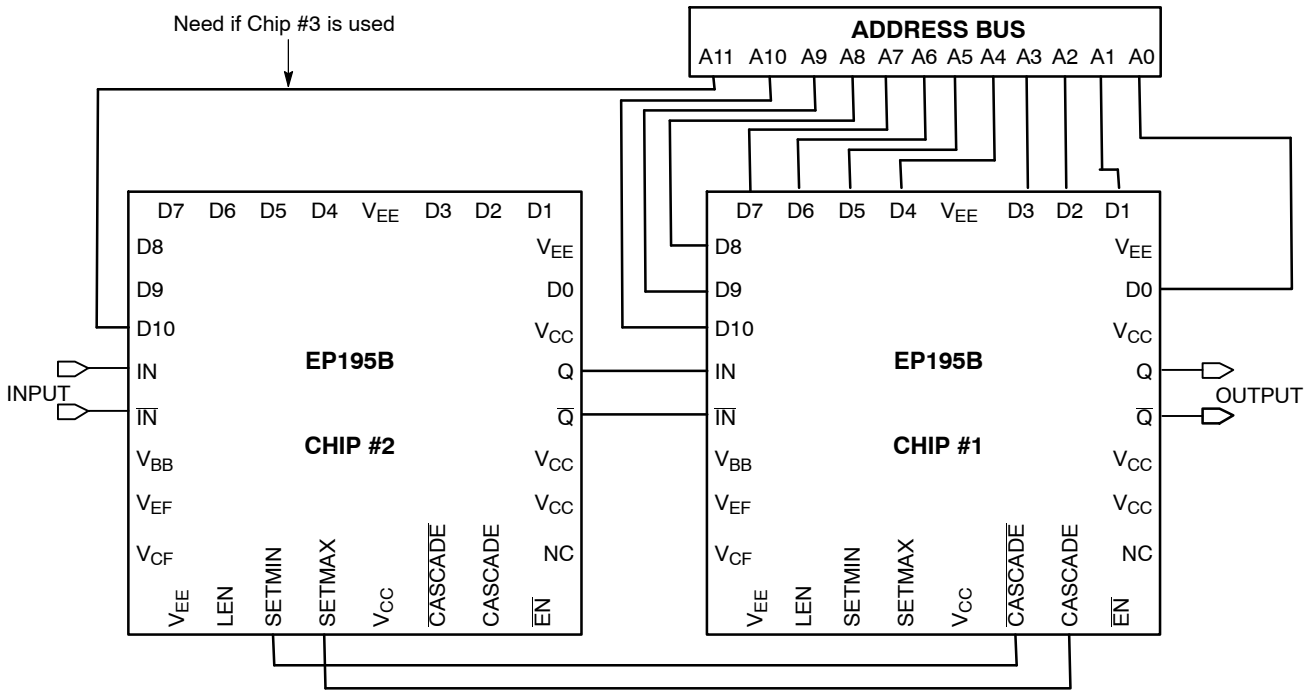
## Cascading Multiple EP195Bs

To increase the programmable range of the EP195B, internal cascade circuitry has been included. This circuitry allows for the cascading of multiple EP195Bs without the need for any external gating. Furthermore, this capability requires only one more address line per added EP195B. Obviously, cascading multiple programmable delay chips will result in a larger programmable range; however, this increase is at the expense of a longer minimum delay.

Figure 5 illustrates the interconnect scheme for cascading two EP195Bs. As can be seen, this scheme can easily be

expanded for larger EP195B chains. The D10 input of the EP195B is the CASCADE control pin. With the interconnect scheme of Figure 5 when D10 is asserted, it signals the need for a larger programmable range than is achievable with a single device and switches output pin CASCADE HIGH and pin  $\overline{CASCADE}$  LOW. The A11 address can be added to generate a cascade output for the next EP195B. For a 2-device configuration, A11 is not required.

# MC100EP195B



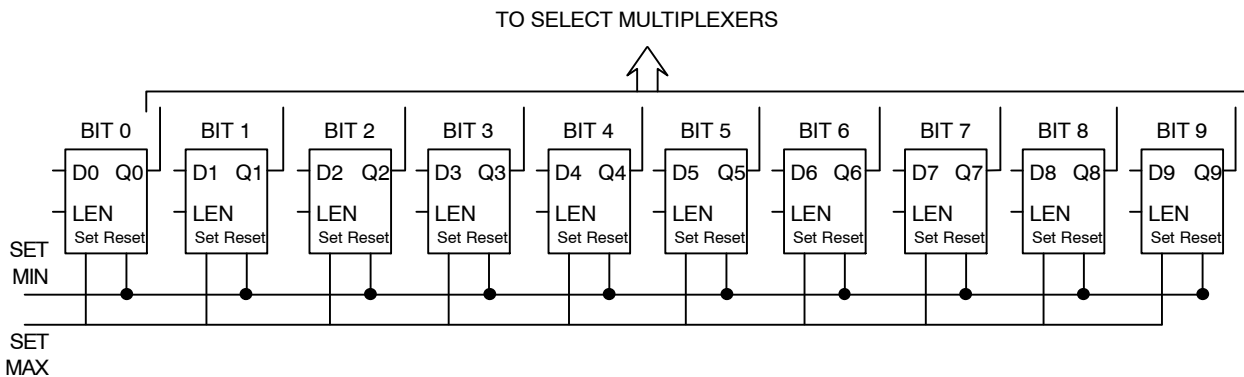
**Figure 5. Cascading Interconnect Architecture**

An expansion of the latch section of the block diagram is pictured in Figure 6. Use of this diagram will simplify the explanation of how the cascade circuitry works. When D10 of chip #1 in Figure 5 is LOW this device's CASCADE output will also be low while the  $\overline{\text{CASCADE}}$  output will be high. In this condition the SET MIN pin of chip #2 will be asserted HIGH and thus all of the latches of chip #2 will be reset and the device will be set at its minimum delay.

Chip #1, on the other hand, will have both SET MIN and SET MAX deasserted so that its delay will be controlled entirely by the address bus A0—A9. If the delay needed is greater than can be achieved with 1023 gate delays

(111111111 on the A0—A9 address bus) D10 will be asserted to signal the need to cascade the delay to the next EP195B device. When D10 is asserted, the SET MIN pin of chip #2 will be deasserted and SET MAX pin asserted resulting in the device delay to be the maximum delay. Table 11 shows the delay time of two EP195B chips in cascade.

To expand this cascading scheme to more devices, one simply needs to connect the D10 pin from the next chip to the address bus and CASCADE outputs to the next chip in the same manner as pictured in Figure 5. The only addition to the logic is the increase of one line to the address bus for cascade control of the second programmable delay chip.



**Figure 6. Expansion of the Latch Section of the EP195B Block Diagram**

# MC100EP195B

**Table 11. Delay Value of Two EP195B Cascaded**

VARIABLE INPUT TO CHIP #1 AND <i>SETMIN</i> FOR CHIP #2												
INPUT FOR CHIP #1											Delay Value	Total Delay Value
D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0		
0	0	0	0	0	0	0	0	0	0	0	0 ps	4400 ps
0	0	0	0	0	0	0	0	0	0	1	10 ps	4410 ps
0	0	0	0	0	0	0	0	0	1	0	20 ps	4420 ps
0	0	0	0	0	0	0	0	0	1	1	30 ps	4430 ps
0	0	0	0	0	0	0	0	1	0	0	40 ps	4440 ps
0	0	0	0	0	0	0	0	1	0	1	50 ps	4450 ps
0	0	0	0	0	0	0	0	1	1	0	60 ps	4460 ps
0	0	0	0	0	0	0	0	1	1	1	70 ps	4470 ps
0	0	0	0	0	0	0	1	0	0	0	80 ps	4480 ps
0	0	0	0	0	0	1	0	0	0	0	160 ps	4560 ps
0	0	0	0	0	1	0	0	0	0	0	220 ps	4720 ps
0	0	0	0	1	0	0	0	0	0	0	640 ps	5040 ps
0	0	0	1	0	0	0	0	0	0	0	1280 ps	5680 ps
0	0	1	0	0	0	0	0	0	0	0	2560 ps	6960 ps
0	1	0	0	0	0	0	0	0	0	0	5120 ps	9520 ps
0	1	1	1	1	1	1	1	1	1	1	10230 ps	14630 ps

VARIABLE INPUT TO CHIP #1 AND <i>SETMAX</i> FOR CHIP #2												
INPUT FOR CHIP #1											Delay Value	Total Delay Value
D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0		
1	0	0	0	0	0	0	0	0	0	0	10240 ps	14640 ps
1	0	0	0	0	0	0	0	0	0	1	10250 ps	14650 ps
1	0	0	0	0	0	0	0	0	1	0	10260 ps	14660 ps
1	0	0	0	0	0	0	0	0	1	1	10270 ps	14670 ps
1	0	0	0	0	0	0	0	1	0	0	10280 ps	14680 ps
1	0	0	0	0	0	0	0	1	0	1	10290 ps	14690 ps
1	0	0	0	0	0	0	0	1	1	0	10300 ps	14700 ps
1	0	0	0	0	0	0	0	1	1	1	10310 ps	14710 ps
1	0	0	0	0	0	0	1	0	0	0	10320 ps	14720 ps
1	0	0	0	0	0	1	0	0	0	0	10400 ps	14800 ps
1	0	0	0	0	1	0	0	0	0	0	10560 ps	14960 ps
1	0	0	0	1	0	0	0	0	0	0	10880 ps	15280 ps
1	0	0	1	0	0	0	0	0	0	0	11520 ps	15920 ps
1	0	1	0	0	0	0	0	0	0	0	12800 ps	17200 ps
1	1	0	0	0	0	0	0	0	0	0	15360 ps	19760 ps
1	1	1	1	1	1	1	1	1	1	1	20470 ps	24870 ps

# MC100EP195B

## Multi-Channel Deskewing

The most practical application for EP195B is in multiple channel delay matching. Slight differences in impedance and cable length can create large timing skews within a high-speed system. To deskew multiple signal channels, each channel can

be sent through each EP195B as shown in Figure 7. One signal channel can be used as reference and the other EP195Bs can be used to adjust the delay to eliminate the timing skews. Nearly any high-speed system can be fine-tuned (as small as 10 ps) to reduce the skew to extremely tight tolerances.

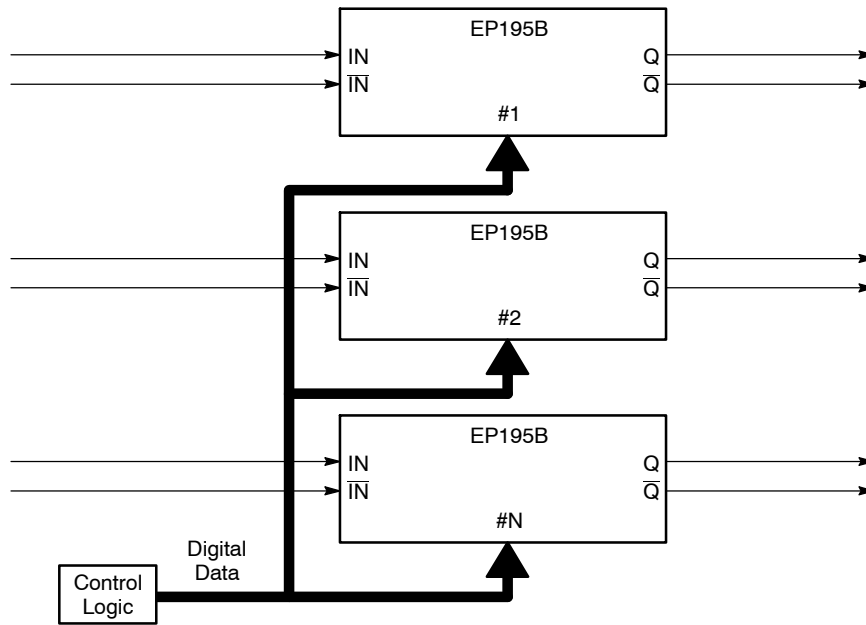


Figure 7. Multiple Channel Deskewing Diagram

## Measure Unknown High Speed Device Delays

EP195Bs provide a possible solution to measure the unknown delay of a device with a high degree of precision. By combining two EP195Bs and EP31 as shown in Figure 8, the delay can be measured. The first EP195B can be set to SETMIN and its output is used to drive the unknown delay device, which in turn drives the input of a D flip-flop of EP31. The second EP195B is triggered along with the first EP195B and its output provides a clock signal for EP31. The programmed delay of the second EP195B is varied to detect the output edge from the unknown delay device.

If the programmed delay through the second EP195B is too long, the flip-flop output will be at logic high. On the other hand, if the programmed delay through the second EP195B is too short, the flip-flop output will be at a logic low. If the programmed delay is correctly fine-tuned in the second EP195B, the flip-flop will bounce between logic high and logic low. The digital code in the second EP195B can be directly correlated into an accurate device delay.

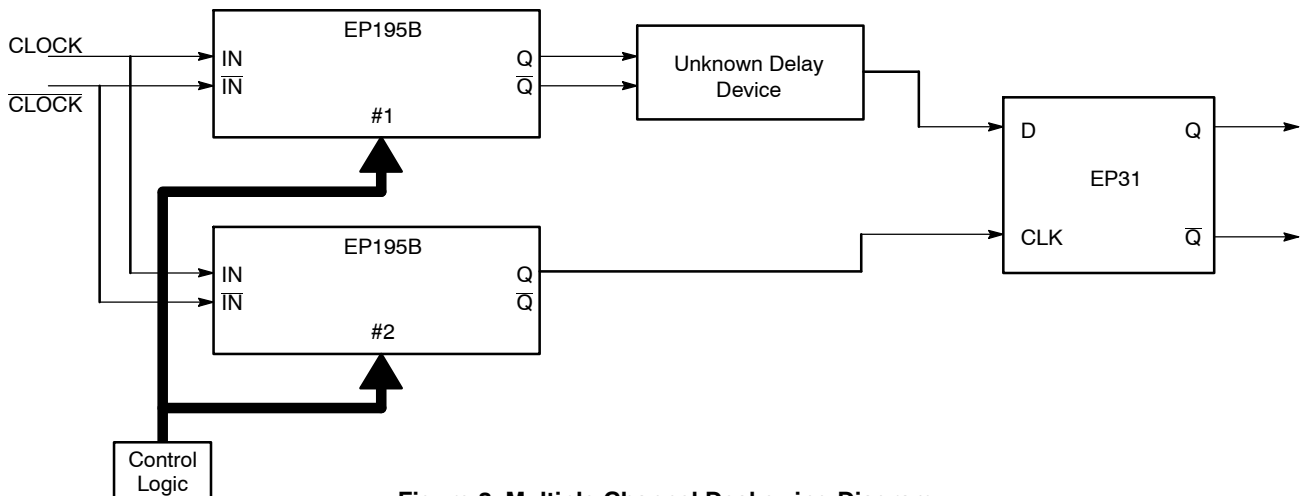
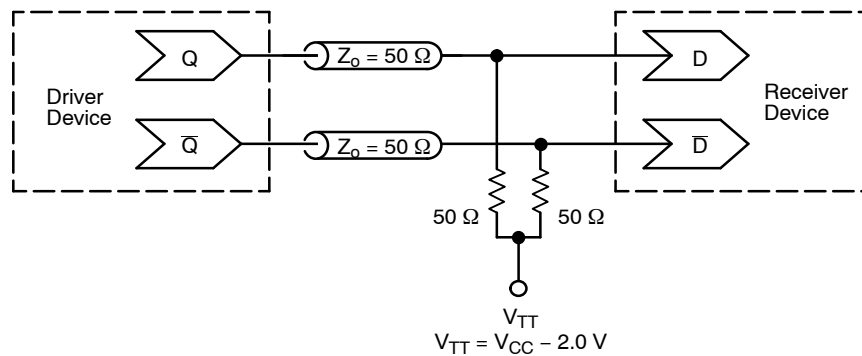


Figure 8. Multiple Channel Deskewing Diagram

## MC100EP195B



**Figure 9. Typical Termination for Output Driver and Device Evaluation  
(See Application Note AND8020/D – Termination of ECL Logic Devices.)**

### ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>
MC100EP195BFAG	LQFP-32 (Pb-Free)	250 Units / tray
MC100EP195BFAR2G	LQFP-32 (Pb-Free)	2000 / Tape & Reel
MC100EP195BMNG	QFN-32 (Pb-Free)	74 Units / Rail
MC100EP195BMNR4G	QFN-32 (Pb-Free)	1000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

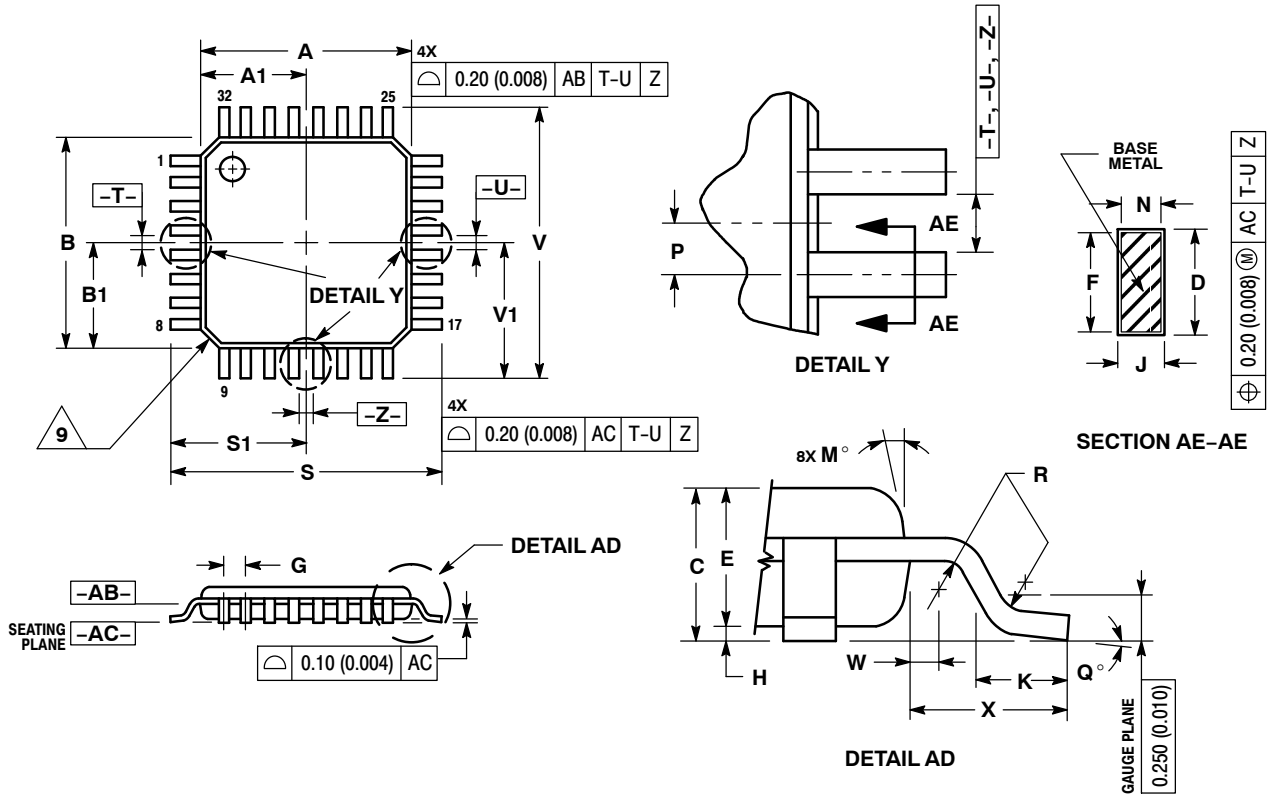
#### Resource Reference of Application Notes

- AN1405/D** – ECL Clock Distribution Techniques
- AN1406/D** – Designing with PECL (ECL at +5.0 V)
- AN1503/D** – ECLinPS™ I/O SPICE Modeling Kit
- AN1504/D** – Metastability and the ECLinPS Family
- AN1568/D** – Interfacing Between LVDS and ECL
- AN1642/D** – The ECL Translator Guide
- AND8001/D** – Odd Number Counters Design
- AND8002/D** – Marking and Date Codes
- AND8020/D** – Termination of ECL Logic Devices
- AND8066/D** – Interfacing with ECLinPS
- AND8090/D** – AC Characteristics of ECL Devices

# MC100EP195B

## PACKAGE DIMENSIONS

32 LEAD LQFP  
CASE 873A-02  
ISSUE C



### NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: MILLIMETER.
- DATUM PLANE -AB- IS LOCATED AT BOTTOM OF LEAD AND IS COINCIDENT WITH THE LEAD WHERE THE LEAD EXITS THE PLASTIC BODY AT THE BOTTOM OF THE PARTING LINE.
- DATUMS -T-, -U-, AND -Z- TO BE DETERMINED AT DATUM PLANE -AB-.
- DIMENSIONS S AND V TO BE DETERMINED AT SEATING PLANE -AC-.
- DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE MOLD PROTRUSION IS 0.250 (0.010) PER SIDE. DIMENSIONS A AND B DO INCLUDE MOLD MISMATCH AND ARE DETERMINED AT DATUM PLANE -AB-.
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. DAMBAR PROTRUSION SHALL NOT CAUSE THE D DIMENSION TO EXCEED 0.520 (0.020).
- MINIMUM SOLDER PLATE THICKNESS SHALL BE 0.0076 (0.0003).
- EXACT SHAPE OF EACH CORNER MAY VARY FROM DEPICTION.

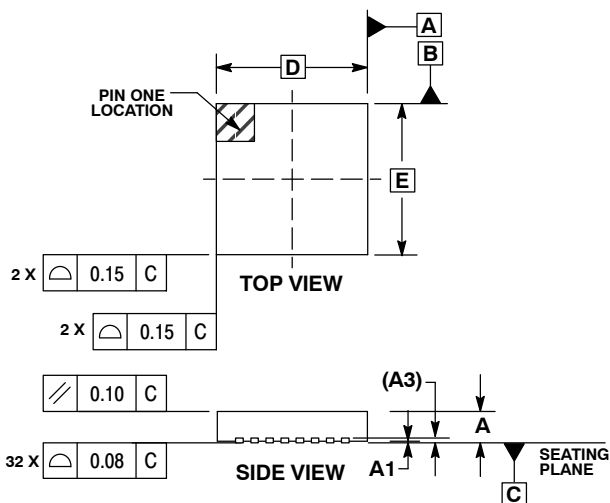
DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	7.000	BSC	0.276	BSC
A1	3.500	BSC	0.138	BSC
B	7.000	BSC	0.276	BSC
B1	3.500	BSC	0.138	BSC
C	1.400	1.600	0.055	0.063
D	0.300	0.450	0.012	0.018
E	1.350	1.450	0.053	0.057
F	0.300	0.400	0.012	0.016
G	0.800	BSC	0.031	BSC
H	0.050	0.150	0.002	0.006
J	0.090	0.200	0.004	0.008
K	0.450	0.750	0.018	0.030
M	12°	REF	12°	REF
N	0.090	0.160	0.004	0.006
P	0.400	BSC	0.016	BSC
Q	1°	5°	1°	5°
R	0.150	0.250	0.006	0.010
S	9.000	BSC	0.354	BSC
S1	4.500	BSC	0.177	BSC
V	9.000	BSC	0.354	BSC
V1	4.500	BSC	0.177	BSC
W	0.200	REF	0.008	REF
X	1.000	REF	0.039	REF



# MC100EP195B

## PACKAGE DIMENSIONS

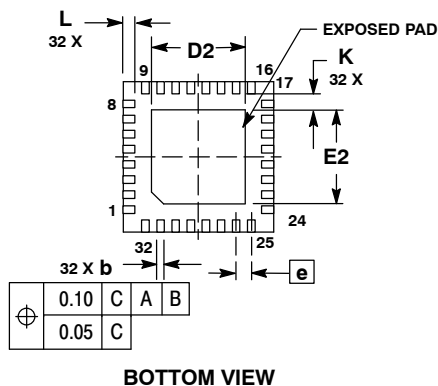
QFN32 5x5, 0.5 P  
CASE 488AM-01  
ISSUE O



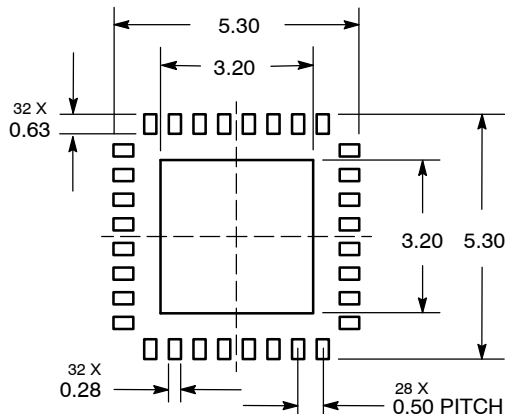
**NOTES:**

1. DIMENSIONS AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS.
3. DIMENSION b APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.25 AND 0.30 MM TERMINAL
4. COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.

DIM	MILLIMETERS		
	MIN	NOM	MAX
A	0.800	0.900	1.000
A1	0.000	0.025	0.050
A3	0.200 REF		
b	0.180	0.250	0.300
D	5.00 BSC		
D2	2.950	3.100	3.250
E	5.00 BSC		
E2	2.950	3.100	3.250
e	0.500 BSC		
K	0.200	---	---
L	0.300	0.400	0.500



**SOLDERING FOOTPRINT\***



DIMENSIONS: MILLIMETERS

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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